## Notice of References Cited Application/Control No. 10/601,877 Examiner Leigh C. Maier Applicant(s)/Patent Under Reexamination BUCHANAN ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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